



TGD P-Channel Enhancement Mode Power MOSFET

Description

The TGD15P25JK uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

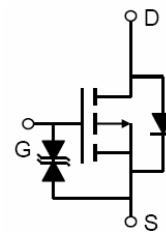
- $V_{DS} = -150V, I_D = -25A$
- $R_{DS(ON)} < 135m\Omega @ V_{GS} = -10V$ (Typ.=120mR)
- $R_{DS(ON)} < 160m\Omega @ V_{GS} = -4.5V$ (Typ.=131mR)
- Super high dense cell design
- Advanced trench process technology
- Reliable and rugged
- High density cell design for ultra low On-Resistance

Application

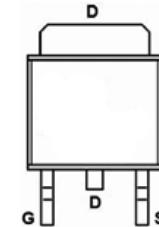
- Portable equipment and battery powered systems

100% UIS TESTED!

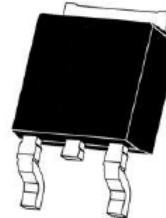
100% ΔV_{ds} TESTED!



Schematic diagram



pin assignment



TO-252-2L top view

Package Marking and Ordering Information

| Device Marking | Device | Device Package | Reel Size | Tape width | Quantity |
|----------------|---------|----------------|-----------|------------|------------|
| 15P25JK | 15P25JK | TO-252-2L | Ø330mm | 12mm | 2500 units |

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

| Parameter | Symbol | Limit | Unit |
|--|---------------------|------------|---------------|
| Drain-Source Voltage | V_{DS} | -150 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | V |
| Drain Current-Continuous | I_D | -25 | A |
| Drain Current-Continuous($T_c=100^\circ C$) | $I_D (100^\circ C)$ | -17 | A |
| Pulsed Drain Current | I_{DM} | -140 | A |
| Maximum Power Dissipation | P_D | 160 | W |
| Derating factor | | 1.3 | W/ $^\circ C$ |
| Operating Junction and Storage Temperature Range | T_J, T_{STG} | -55 To 150 | $^\circ C$ |

**Thermal Characteristic**

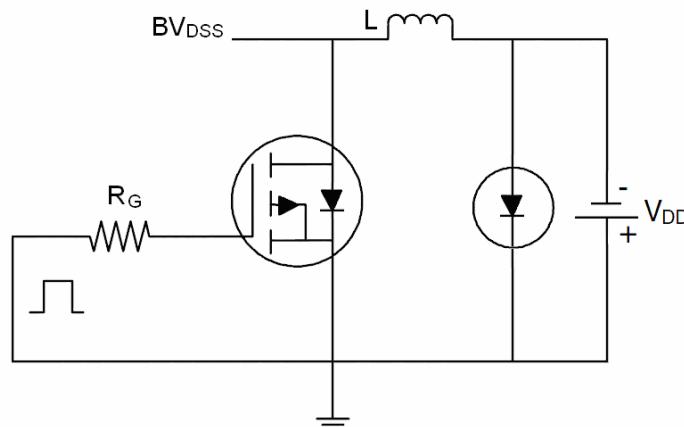
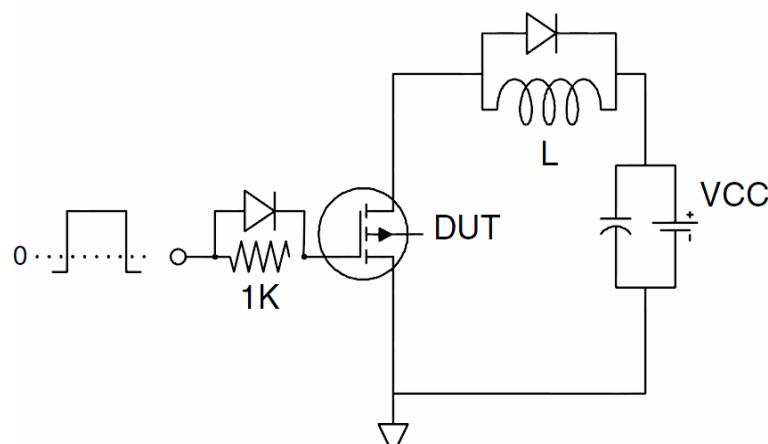
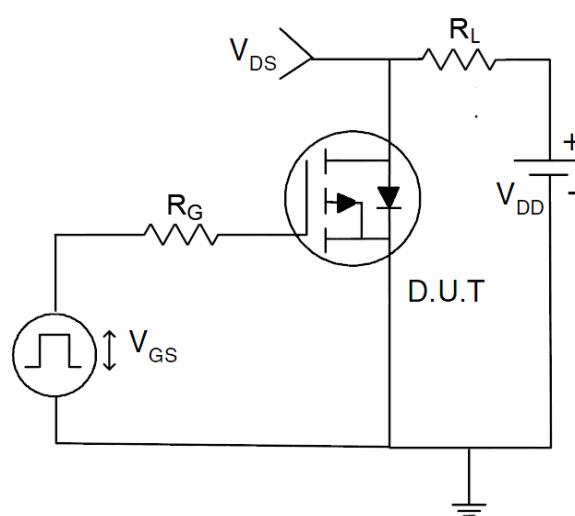
| | | | |
|---|-----------------|-----|------|
| Thermal Resistance,Junction-to-Case ^(Note 2) | $R_{\theta JC}$ | 0.8 | °C/W |
|---|-----------------|-----|------|

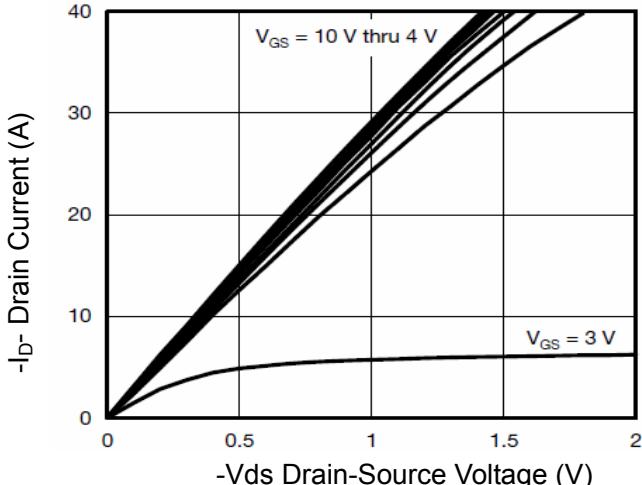
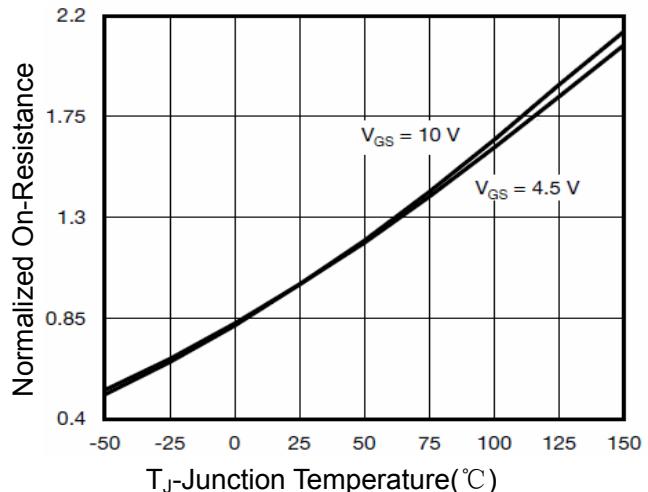
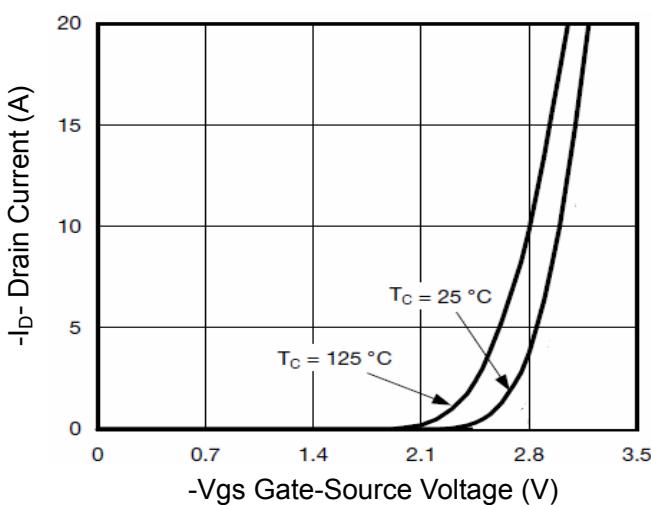
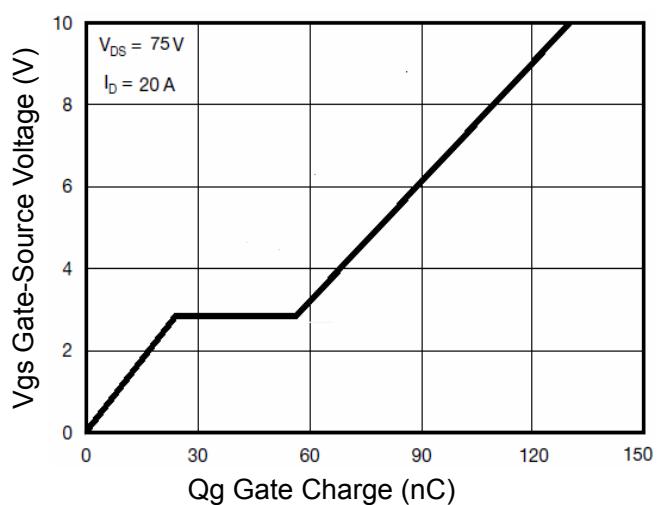
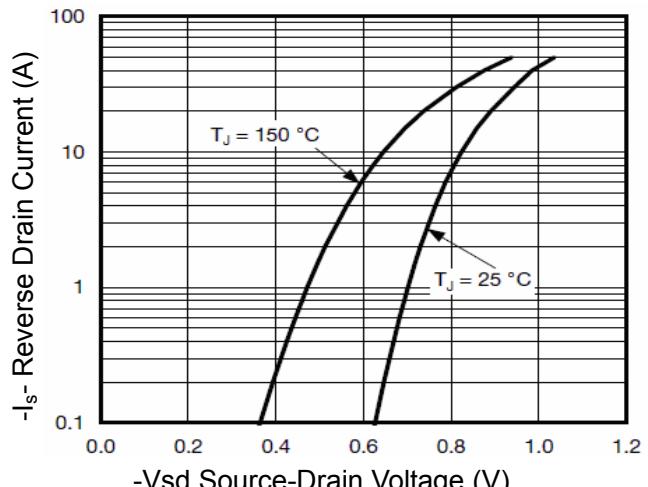
Electrical Characteristics ($T_c=25^\circ C$ unless otherwise noted)

| Parameter | Symbol | Condition | Min | Typ | Max | Unit |
|--|--------------|---|------|------|----------|-----------|
| Off Characteristics | | | | | | |
| Drain-Source Breakdown Voltage | V_{DSS} | $V_{GS}=0V, I_D=-250\mu A$ | -145 | -155 | - | V |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS}=-145V, V_{GS}=0V$ | - | - | 1 | μA |
| Gate-Body Leakage Current | I_{GSS} | $V_{GS}=\pm 20V, V_{DS}=0V$ | - | - | ± 10 | μA |
| On Characteristics ^(Note 3) | | | | | | |
| Gate Threshold Voltage | $V_{GS(th)}$ | $V_{DS}=V_{GS}, I_D=-250\mu A$ | -1.5 | -1.9 | -3 | V |
| Drain-Source On-State Resistance | $R_{DS(ON)}$ | $V_{GS}=-10V, I_D=-20A$ | - | 120 | 135 | $m\Omega$ |
| | | $V_{GS}=-4.5V, I_D=-20A$ | - | 131 | 160 | |
| Forward Transconductance | g_{FS} | $V_{DS}=-5V, I_D=-20A$ | 5 | - | - | S |
| Dynamic Characteristics ^(Note 4) | | | | | | |
| Input Capacitance | C_{iss} | $V_{DS}=-75V, V_{GS}=0V, F=1.0MHz$ | - | 7650 | - | PF |
| Output Capacitance | C_{oss} | | - | 148 | - | PF |
| Reverse Transfer Capacitance | C_{rss} | | - | 131 | - | PF |
| Switching Characteristics ^(Note 4) | | | | | | |
| Turn-on Delay Time | $t_{d(on)}$ | $V_{DD}=-75V, I_D=-20A, V_{GS}=-10V, R_{GEN}=9.1\Omega$ | - | 17 | - | nS |
| Turn-on Rise Time | t_r | | - | 80 | - | nS |
| Turn-Off Delay Time | $t_{d(off)}$ | | - | 45 | - | nS |
| Turn-Off Fall Time | t_f | | - | 65 | - | nS |
| Total Gate Charge | Q_g | $V_{DS}=-75V, I_D=-20A, V_{GS}=-10V$ | - | 137 | - | nC |
| Gate-Source Charge | Q_{gs} | | - | 25 | - | nC |
| Gate-Drain Charge | Q_{gd} | | - | 28 | - | nC |
| Drain-Source Diode Characteristics | | | | | | |
| Diode Forward Voltage ^(Note 3) | V_{SD} | $V_{GS}=0V, I_S=-25A$ | - | - | -1.2 | V |
| Diode Forward Current ^(Note 2) | I_S | - | - | - | -25 | A |
| Reverse Recovery Time | t_{rr} | $T_J = 25^\circ C, IF = -25A$ $di/dt = 100A/\mu s$ ^(Note 3) | - | 90 | - | nS |
| Reverse Recovery Charge | Q_{rr} | | - | 105 | - | nC |

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, $t \leq 10$ sec.
3. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$.
4. Guaranteed by design, not subject to production
5. EAS condition: $T_j=25^\circ C, V_{DD}=-75V, V_G=-10V, L=0.5mH, R_g=25\Omega$

Test Circuit
1) E_{AS} Test Circuit

2) Gate Charge Test Circuit

3) Switch Time Test Circuit


Typical Electrical and Thermal Characteristics (Curves)

Figure 1 Output Characteristics

Figure 4 Rdson-JunctionTemperature

Figure 2 Transfer Characteristics

Figure 5 Gate Charge

Figure 6 Source- Drain Diode Forward

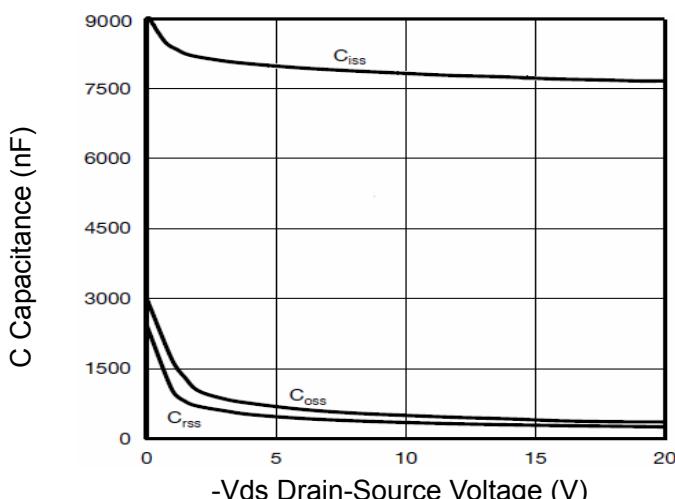


Figure 7 Capacitance vs Vds

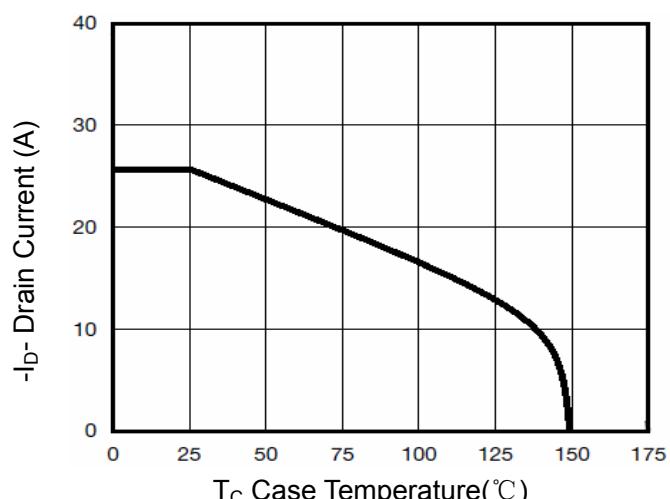


Figure 9 Drain Current vs Case Temperature

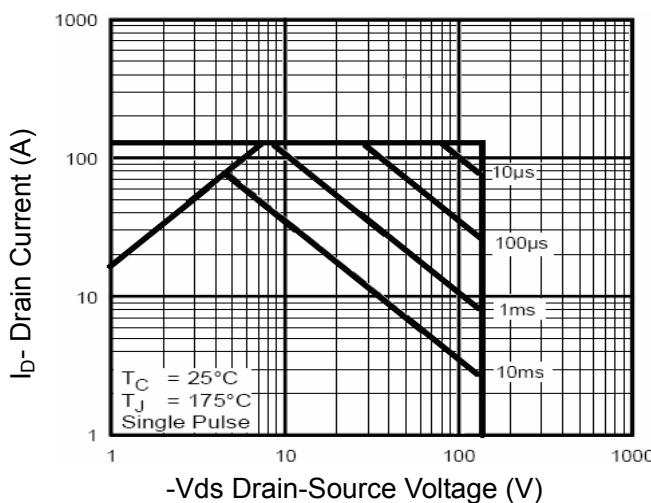


Figure 8 Safe Operation Area

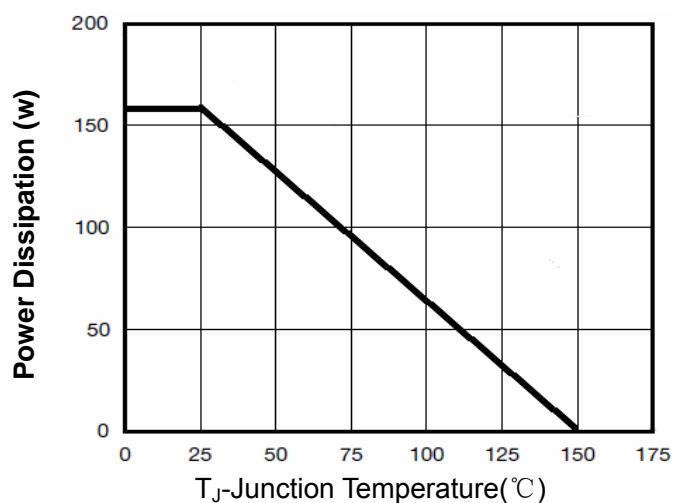


Figure 10 Power De-rating

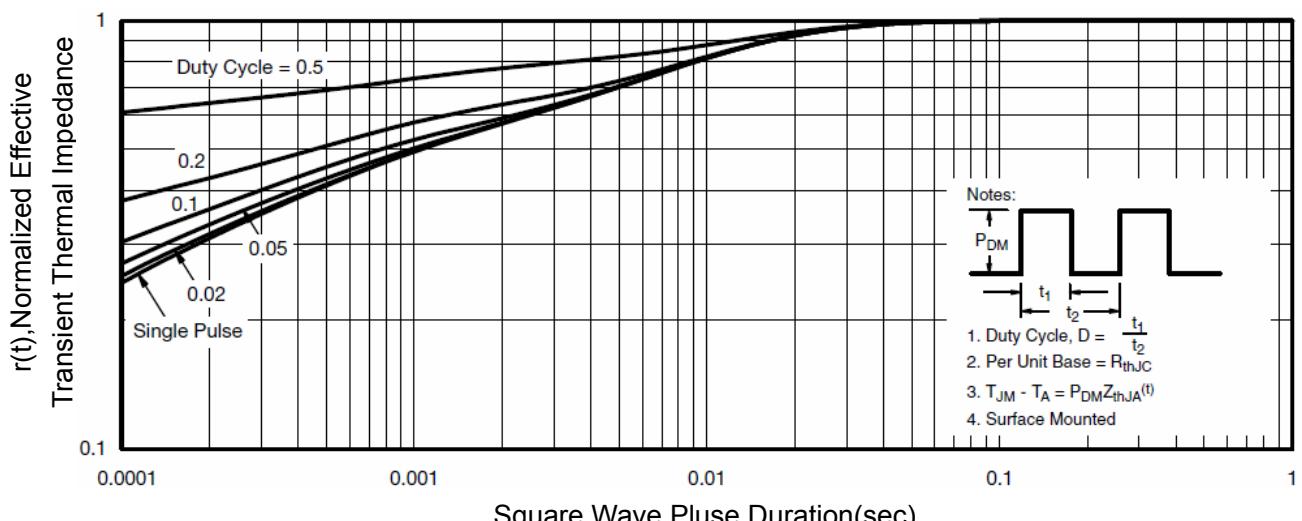
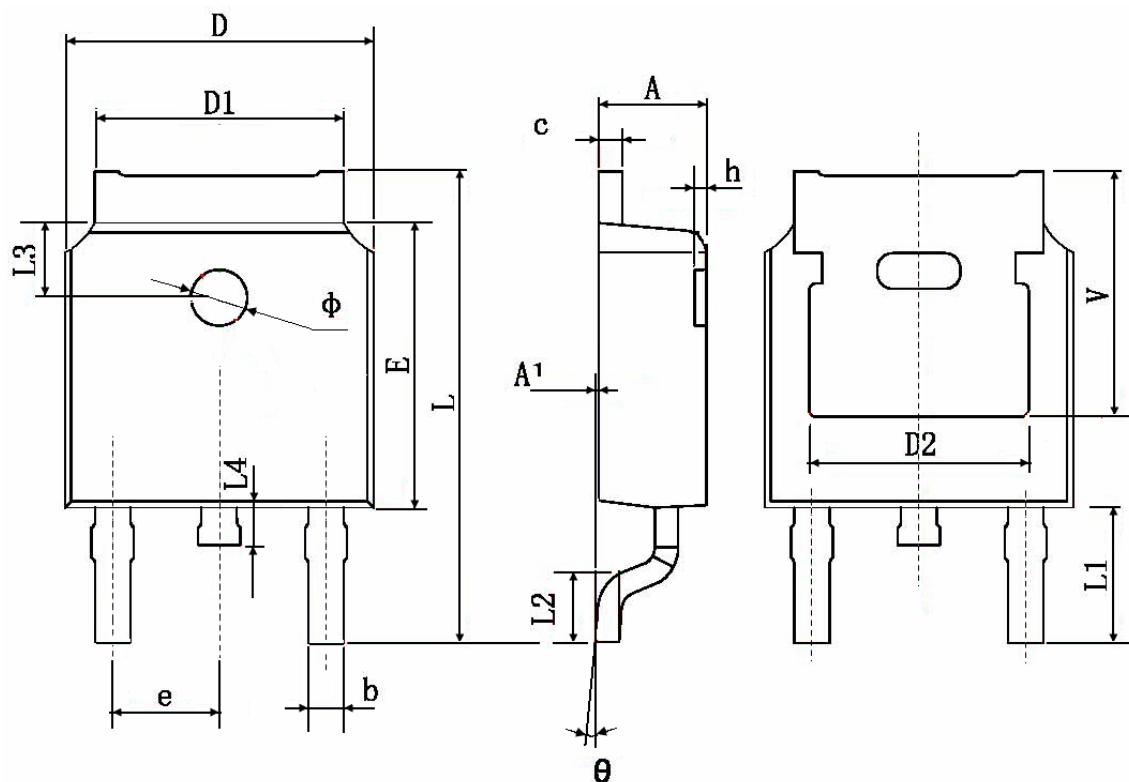


Figure 11 Normalized Maximum Transient Thermal Impedance

TO-252 Package Information


| Symbol | Dimensions In Millimeters | | Dimensions In Inches | |
|----------|---------------------------|--------|----------------------|-------|
| | Min. | Max. | Min. | Max. |
| A | 2.200 | 2.400 | 0.087 | 0.094 |
| A1 | 0.000 | 0.127 | 0.000 | 0.005 |
| b | 0.660 | 0.860 | 0.026 | 0.034 |
| c | 0.460 | 0.580 | 0.018 | 0.023 |
| D | 6.500 | 6.700 | 0.256 | 0.264 |
| D1 | 5.100 | 5.460 | 0.201 | 0.215 |
| D2 | 4.83 TYP. | | 0.190 TYP. | |
| E | 6.000 | 6.200 | 0.236 | 0.244 |
| e | 2.186 | 2.386 | 0.086 | 0.094 |
| L | 9.800 | 10.400 | 0.386 | 0.409 |
| L1 | 2.900 TYP. | | 0.114 TYP. | |
| L2 | 1.400 | 1.700 | 0.055 | 0.067 |
| L3 | 1.600 TYP. | | 0.063 TYP. | |
| L4 | 0.600 | 1.000 | 0.024 | 0.039 |
| ϕ | 1.100 | 1.300 | 0.043 | 0.051 |
| θ | 0° | 8° | 0° | 8° |
| h | 0.000 | 0.300 | 0.000 | 0.012 |
| V | 5.350 TYP. | | 0.211 TYP. | |